

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

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Application Number
10/040,122

Applicant(s)
SCOTT ET AL.

Filing Date
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Group Art Unit
2825

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10/040122

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WD		6,256,759	07-03-01	BHAWMIK ET AL.			
WD		5,737,340	04-07-98	TAMARAPALLI ET AL.			
WD		6,070,261	05-30-00	TAMARAPALLI ET AL.			
WD		6,038,691	03-14-00	NAKAO ET AL.			
WD		5,828,828	10-27-98	LIN ET AL.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

WD		"TEST POINT INSERTION FOR SCAN-BASED BIST" SEISS ET AL. PROCEEDING OF THE EUROPEAN TEST CONFERENCE, pp. 253, 1991.
WD		"TESTABILITY-DRIVEN RANDOM TEST-PATTERN GENERATION" LISANKE ET AL. , IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN, Vol. CAD-6, Nov. 1987, pp. 1082-1087.
WD		"ON TESTABILITY ANALYSIS OF COMBINATIONAL NETWORKS" BRGLEZ ET AL, PROCEEDINGS OF INTERNATIONS SYMPOSIUM ON CIRCUITS AND SYSTEMS, pp.221-225, 1984.
WD		"ON GENERATING OPTIMAL SIGNAL PROBABILITIES FOR RANDOM TESTS: A GENETIC APPROACH", SRINIVAS ET AL. VLSI DESIGN, 1996, VOL. 4, NO.3, pp 207-215.
WD		"STATISTICAL FAULT ANALYSIS", JAIN ET AL. IEEE DESIGN & TEST OF COMPUTERS, VOL. 2, NO.2 pp. 38-44.

EXAMINER

DATE CONSIDERED **9/2003**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.